

**Maximum Ratings / Höchstzulässige Werte**

Parameter	Condition	Symbol	Value	Unit
<b>Input Rectifier Bridge</b>				
<b>Gleichrichter</b>				
Repetitive peak reverse voltage Periodische Rückw. Spitzensperrspannung		$V_{RRM}$	1600	
Forward current per diode Dauergrenzstrom	DC current $T_h=80^{\circ}\text{C};$ $T_c=80^{\circ}\text{C}$	$I_{FAV}$	33 40-limited by wires	A
Surge forward current Stoßstrom Grenzwert	$t_p=10\text{ms}$ $T_j=25^{\circ}\text{C}$	$I_{FSM}$	250	A
$I^2t$ -value Grenzlastintegral	$t_p=10\text{ms}$ $T_j=25^{\circ}\text{C}$	$I^2t$	310	$\text{A}^2\text{s}$
Power dissipation per Diode Verlustleistung pro Diode	$T_j=150^{\circ}\text{C}$ $T_h=80^{\circ}\text{C}$ $T_c=80^{\circ}\text{C}$	$P_{tot}$	39 60,4	W

**Transistor Inverter**  
**Transistor Wechselrichter**

Collector-emitter break down voltage Kollektor-Emitter-Sperrspannung		$V_{CE}$	1200	V
DC collector current Kollektor-Dauergleichstrom	$T_j=150^{\circ}\text{C}$ $T_h=80^{\circ}\text{C},$ $T_c=80^{\circ}\text{C}$	$I_C$	30 40 limited by pin	A
Repetitive peak collector current Periodischer Kollektorspitzenstrom	$t_p=1\text{ms}$ $T_h=80^{\circ}\text{C}$	$I_{cpuls}$	50	A
Power dissipation per IGBT Verlustleistung pro IGBT	$T_j=150^{\circ}\text{C}$ $T_h=80^{\circ}\text{C}$ $T_c=80^{\circ}\text{C}$	$P_{tot}$	56 100	W
Gate-emitter peak voltage Gate-Emitter-Spitzenspannung		$V_{GE}$	$\pm 20$	V
SC withstand time Kurzschlußverhalten	$T_j \leq 150^{\circ}\text{C}$ $V_{CE}=600/1200\text{V}$	$V_{GE}=15\text{V}$ $t_{SC}$		us

**Diode Inverter**  
**Diode Wechselrichter**

DC forward current Dauergleichstrom	$T_j=150^{\circ}\text{C}$ $T_h=80^{\circ}\text{C},$ $T_c=80^{\circ}\text{C}$	$I_F$	25 40 limited by pin	A
Repetitive peak forward current Periodischer Spitzenstrom	$t_p=1\text{ms}$ $T_h=80^{\circ}\text{C}$	$I_{FRM}$	50	A
Power dissipation per Diode Verlustleistung pro Diode	$T_j=150^{\circ}\text{C}$ $T_h=80^{\circ}\text{C}$ $T_c=80^{\circ}\text{C}$	$P_{tot}$	30 60,0	W

flow PIM<sup>®</sup> 1 (2<sup>nd</sup> gen.), 1200V

**Maximum Ratings / Höchstzulässige Werte**

Parameter	Condition	Symbol	Value	Unit
<b>Transistor Brake</b>				
<b>Transistor Bremse</b>				
Collector-emitter break down voltage Kollektor-Emitter-Sperrspannung		$V_{CE}$	1200	V
DC collector current Kollektor-Dauergleichstrom	$T_j=150^{\circ}C$ $T_h=80^{\circ}C$ , $T_c=80^{\circ}C$	$I_C$	24 30-limited by wires	A
Repetitive peak collector current Periodischer Kollektorspitzenstrom	$t_p=1ms$ $T_h=80^{\circ}C$	$I_{cpuls}$	48	A
Power dissipation per IGBT Verlustleistung pro IGBT	$T_j=150^{\circ}C$ $T_h=80^{\circ}C$ $T_c=80^{\circ}C$	$P_{tot}$	50 86	W
Gate-emitter peak voltage Gate-Emitter-Spitzenspannung		$V_{GE}$	$\pm 20$	V
SC withstand time Kurzschlußverhalten	$T_j \leq 150^{\circ}C$ $V_{GE}=15V$ $V_{CE}=600/1200 V$	$t_{SC}$		us

**Diode Brake**

**Diode Brake**

DC forward current Dauergleichstrom	$T_j=150^{\circ}C$ $T_h=80^{\circ}C$ , $T_c=80^{\circ}C$	$I_F$	7 10	A
Repetitive peak forward current Periodischer Spitzenstrom	$t_p=1ms$ $T_h=80^{\circ}C$	$I_{FRM}$	14	A
Power dissipation per Diode Verlustleistung pro Diode	$T_j=150^{\circ}C$ $T_h=80^{\circ}C$ $T_c=80^{\circ}C$	$P_{tot}$	13 20	W

**Thermal properties**

**Thermische Eigenschaften**

max. Chip temperature max. Chiptemperatur		$T_{imax}$	150	$^{\circ}C$
Storage temperature Lagertemperatur		$T_{stg}$	-40...+125	$^{\circ}C$
Operation temperature Betriebstemperatur		$T_{op}$	-40...+125	$^{\circ}C$

**Insulation properties**

**Modulisolation**

Insulation voltage Isolationsspannung	$t=1min$	$V_{is}$	4000	Vdc
Creepage distance Kriechstrecke			min 12,7	mm
Clearance Luftstrecke			min 12,7	mm

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**Characteristic values**

Description	Symbol						Datasheet values			Unit
		T(C°)	Other conditions (Rgon-Rgoff)	VGE(V) VGS(V)	VCE(V) VDS(V)	IC(A) IF(A) Id(A)	Min	Typ	Max	

**Input Rectifier Bridge  
Gleichrichter**

Forward voltage Durchlaßspannung	V <sub>F</sub>	T <sub>j</sub> =25°C T <sub>j</sub> =125°C				30		1,18 1,15	1,35	V
Threshold voltage (for power loss calc. only) Schleusenspannung	V <sub>to</sub>	T <sub>j</sub> =25°C T <sub>j</sub> =125°C				30		0,9 0,78		V
Slope resistance (for power loss calc. only) Ersatzwiderstand	r <sub>t</sub>	T <sub>j</sub> =25°C T <sub>j</sub> =125°C				30		0,009 0,012		Ohm
Reverse current Sperrstrom	I <sub>r</sub>	T <sub>j</sub> =25°C T <sub>j</sub> =150°C			1200				0,02 4	mA
Thermal resistance chip to heatsink per chip Wärmewiderstand Chip-Kühlkörper pro Chip	R <sub>thJH</sub>		Thermal grease thickness≤50um					1,8		K/W
Thermal resistance chip to case per chip Wärmewiderstand Chip-Gehäuse pro Chip	R <sub>thJC</sub>		Wärmeleitpaste Dicke≤50um λ = 0,61 W/mK					1,2		K/W

**Transistor Inverter  
Transistor Wechselrichter**

Gate emitter threshold voltage Gate-Schwellenspannung	V <sub>GE(th)</sub>	T <sub>j</sub> =25°C T <sub>j</sub> =125°C	V <sub>CE</sub> =V <sub>GE</sub>				0,002	5	5,8	6,5	V
Collector-emitter saturation voltage Kollektor-Emitter Sättigungsspannung	V <sub>CE(sat)</sub>	T <sub>j</sub> =25°C T <sub>j</sub> =125°C		15		35	1,3	1,7	2,3		V
Collector-emitter cut-off current incl. Diode Kollektor-Emitter Reststrom	I <sub>CES</sub>	T <sub>j</sub> =25°C T <sub>j</sub> =125°C		0	1200				0,25		mA
Gate-emitter leakage current Gate-Emitter Reststrom	I <sub>GES</sub>	T <sub>j</sub> =25°C T <sub>j</sub> =125°C		30	0				650		nA
Turn-on delay time Einschaltverzögerungszeit	t <sub>d(on)</sub>	T <sub>j</sub> =25°C T <sub>j</sub> =125°C	Rgon=27Ohm Rgoff=27Ohm	15	600	35			tdb		ns
Rise time Anstiegszeit	t <sub>r</sub>	T <sub>j</sub> =25°C T <sub>j</sub> =125°C	Rgon=27Ohm Rgoff=27Ohm	15	600	35			tdb		ns
Turn-off delay time Abschaltverzögerungszeit	t <sub>d(off)</sub>	T <sub>j</sub> =25°C T <sub>j</sub> =125°C	Rgon=27Ohm Rgoff=27Ohm	15	600	35			tdb		ns
Fall time Fallzeit	t <sub>f</sub>	T <sub>j</sub> =25°C T <sub>j</sub> =125°C	Rgon=27Ohm Rgoff=27Ohm	15	600	35			tdb		ns
Turn-on energy loss per pulse Einschaltverlustenergie pro Puls	E <sub>on</sub>	T <sub>j</sub> =25°C T <sub>j</sub> =125°C							tdb		mWs
Turn-off energy loss per pulse Abschaltverlustenergie pro Puls	E <sub>off</sub>	T <sub>j</sub> =25°C T <sub>j</sub> =125°C							tdb		mWs
Input capacitance Eingangskapazität	C <sub>iss</sub>	T <sub>j</sub> =25°C T <sub>j</sub> =125°C	f=1MHz	0	25				2530		pF
Output capacitance Ausgangskapazität	C <sub>oss</sub>	T <sub>j</sub> =25°C T <sub>j</sub> =125°C	f=1MHz	0	25				132		pF
Reverse transfer capacitance Rückwirkungskapazität	C <sub>rss</sub>	T <sub>j</sub> =25°C T <sub>j</sub> =125°C	f=1MHz	0	25				115		pF
Gate charge Gate Ladung	Q <sub>Gate</sub>	T <sub>j</sub> =25°C T <sub>j</sub> =125°C									nC
Thermal resistance chip to heatsink per chip Wärmewiderstand Chip-Kühlkörper pro Chip	R <sub>thJH</sub>		Thermal grease thickness≤50um					1,24			K/W
Thermal resistance chip to case per chip Wärmewiderstand Chip-Gehäuse pro Chip	R <sub>thJC</sub>		Wärmeleitpaste Dicke≤50um λ = 0,61 W/mK					0,7			K/W
Coupled thermal resistance inverter diode-transistor Gekoppelte Wärmewiderstand Wechselrichter Diode-Transistor	R <sub>thJH</sub>		Thermal grease thickness≤50um Wärmeleitpaste Dicke≤50um λ = 0,61 W/mK								K/W

**flow PIM® 1 (2<sup>nd</sup> gen.), 1200V**

**Characteristic values**

Description	Symbol	Datasheet values						Unit		
		T(C°)	Other conditions (Rgon-Rgoff)	VGE(V) VGS(V)	VCE(V) VDS(V)	IC(A) IF(A) Id(A)	Min		Typ	Max
<b>Diode Inverter</b>										
<b>Diode Wechselrichter</b>										
Diode forward voltage Durchlaßspannung	V <sub>F</sub>	T <sub>j</sub> =25°C T <sub>j</sub> =125°C				35		2,2 1,8	3,05	V
Peak reverse recovery current Rückstromspitze	I <sub>RRM</sub>	T <sub>j</sub> =25°C T <sub>j</sub> =125°C	Rgon=40Ohm	15	600	35		tdb		A
Reverse recovery time Sperrverzögerungszeit	t <sub>rr</sub>	T <sub>j</sub> =25°C T <sub>j</sub> =125°C	Rgon=40Ohm	15	600	35		tdb		ns
Reverse recovered charge Sperrverzögerungsladung	Q <sub>rr</sub>	T <sub>j</sub> =25°C T <sub>j</sub> =125°C	Rgon=40Ohm	15	600	35		tdb		uC
Reverse recovered energy Sperrverzögerungsenergie	E <sub>rec</sub>		Rgon=40Ohm	15	600	35		tdb		mWs
Thermal resistance chip to heatsink per chip Wärmewiderstand Chip-Kühlkörper pro Chip	R <sub>thJH</sub>		Thermal grease thickness≤50um					2,5		K/W
Thermal resistance chip to case per chip Wärmewiderstand Chip-Gehäuse pro Chip	R <sub>thJC</sub>		Wärmeleitpaste Dicke≤50um λ = 0,61 W/mK					1,5		K/W
Coupled thermal resistance inverter transistor-diode Gekoppelte Wärmewiderstand Wechselrichter Transistor-Diode	R <sub>thJH</sub>		Thermal grease thickness≤50um Wärmeleitpaste Dicke≤50um λ = 0,61 W/mK					tdb		K/W

**Transistor BRC**

**Transistor BRC**

Gate emitter threshold voltage Gate-Schwellenspannung	V <sub>GE(th)</sub>	T <sub>j</sub> =25°C T <sub>j</sub> =125°C	V <sub>CE</sub> =V <sub>GE</sub>			0,001	5	5,8	6,5	V
Collector-emitter saturation voltage Kollektor-Emitter Sättigungsspannung	V <sub>CE(sat)</sub>	T <sub>j</sub> =25°C T <sub>j</sub> =125°C		15		25	1,3	1,7	2,2	V
Collector-emitter cut-off Kollektor-Emitter Reststrom	I <sub>CES</sub>	T <sub>j</sub> =25°C T <sub>j</sub> =125°C		0	1200				0,15	mA
Gate-emitter leakage current Gate-Emitter Reststrom	I <sub>GES</sub>	T <sub>j</sub> =25°C T <sub>j</sub> =125°C		30	0				650	nA
Turn-on delay time Einschaltverzögerungszeit	t <sub>d(on)</sub>	T <sub>j</sub> =25°C T <sub>j</sub> =125°C	Rgon=36Ohm Rgoff=36Ohm	15	600	25		90		ns
Rise time Anstiegszeit	t <sub>r</sub>	T <sub>j</sub> =25°C T <sub>j</sub> =125°C	Rgon=36Ohm Rgoff=36Ohm	15	600	25		45		ns
Turn-off delay time Abschaltverzögerungszeit	t <sub>d(off)</sub>	T <sub>j</sub> =25°C T <sub>j</sub> =125°C	Rgon=36Ohm Rgoff=36Ohm	15	600	25		520		ns
Fall time Fallzeit	t <sub>f</sub>	T <sub>j</sub> =25°C T <sub>j</sub> =125°C	Rgon=36Ohm Rgoff=36Ohm	15	600	25		90		ns
Turn-on energy loss per pulse Einschaltverlustenergie pro Puls	E <sub>on</sub>	T <sub>j</sub> =25°C T <sub>j</sub> =125°C								uWs
Turn-off energy loss per pulse Abschaltverlustenergie pro Puls	E <sub>off</sub>	T <sub>j</sub> =25°C T <sub>j</sub> =125°C								uWs
Input capacitance Eingangskapazität	C <sub>iss</sub>	T <sub>j</sub> =25°C T <sub>j</sub> =125°C	f=1MHz	0	25			1808		pF
Output capacitance Ausgangskapazität	C <sub>oss</sub>	T <sub>j</sub> =25°C T <sub>j</sub> =125°C	f=1MHz	0	25			95		pF
Reverse transfer capacitance Rückwirkungskapazität	C <sub>rss</sub>	T <sub>j</sub> =25°C T <sub>j</sub> =125°C	f=1MHz	0	25			82		pF
Gate charge Gate Ladung	Q <sub>Gate</sub>	T <sub>j</sub> =25°C T <sub>j</sub> =125°C								nC
Thermal resistance chip to heatsink per chip Wärmewiderstand Chip-Kühlkörper pro Chip	R <sub>thJH</sub>		Thermal grease thikness≤50um					1,38		K/W
Thermal resistance chip to case per chip Wärmewiderstand Chip-Gehäuse pro Chip	R <sub>thJC</sub>		Wärmeleitpaste Dicke≤50um λ = 0,61 W/mK					0,9		K/W

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**Characteristic values**

Description	Symbol						Datasheet values			Unit
		T(C°)	Other conditions (Rgon-Rgoff)	VGE(V) VGS(V)	VCE(V) VDS(V)	IC(A) IF(A) Id(A)	Min	Typ	Max	

**Diode BRC**

**Diode BRC**

Diode forward voltage Durchlaßspannung	$V_F$	Tj=25°C Tj=150°C				6		1,6		V
Reverse current Sperrstrom	$I_r$	Tj=25°C Tj=125°C						TBD		µA
Peak reverse recovery current Rückstromspitze	$I_{RRM}$	Tj=25°C Tj=125°C	Rgon=52Ohm	15	300	5		TBD		A
Reverse recovery time Sperrverzögerungszeit	$t_{rr}$	Tj=25°C Tj=125°C	Rgon=52Ohm	15	300	5		TBD		ns
Reverse recovered charge Sperrverzögerungsladung	$Q_{rr}$	Tj=25°C Tj=125°C	Rgon=52Ohm	15	300	5		TBD		µC
Reverse recovery energy Sperrverzögerungsenergie	$E_{rec}$	Tj=25°C Tj=125°C	Rgon=52Ohm	15	300	5		TBD		µWs
Thermal resistance chip to heatsink per chip Wärmewiderstand Chip-Kühlkörper pro Chip	$R_{thJH}$		Thermal grease thickness≤50um					5,1		K/W
Thermal resistance chip to case per chip Wärmewiderstand Chip-Gehäuse pro Chip	$R_{thJC}$		Warmeleitpaste Dicke≤50um $\lambda = 0,61 \text{ W/mK}$					3,8		K/W

**NTC-Thermistor**

**NTC-Widerstand**

Rated resistance Nennwiderstand	$R_{25}$	Tj=25°C	Tol. ±5%				20,9	22	23,1	kOhm
Deviation of R100 Abweichung von R100	$D_{R/R}$	Tc=100°C	R100=1503W					2,9		%/K
Power dissipation given Epcos-Typ Verlustleistung Epcos-Typ angeben	P	Tj=25°C						210		mW
B-value B-Wert	$B_{(25/100)}$	Tj=25°C	Tol. ±3%					3980		K